VLSI Systems Designs(SoC DM): Final Exam (2016 Fall)

10:30 ~ 11:50, 12/14/2014, Prof. Jinsang Kim

Assume that a matched unit inverter has widths of 45nm for nMOS and 90nm for pMOS, respectively. The 45nm process technology uses the following parameters unless stated otherwise: $V_{DD} = 1 \, V$, $V_{DD} = 1$

1. (35pts) You need to decide the minimum delay and widths of logic gates in the following circuit. Input and output capacitances are denoted based on a unit matched inverter (5u gate width means width is 5 times larger than that of the unit matched inverter). ND3 = 3 input NAND, NR2 = 2 input NOR, I = Inverter, respectively.

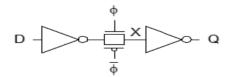
CIN = 5u gate width
$$\frac{A}{\phi}$$
 ND3 $\frac{Z}{\phi}$ COUT = 115u gate width

- a) calculate the logical efforts of all logic gates (ND3, NR2, and I) on the path "A" ~ "Z". (6pts)
- b) calculate path logical effort, path electrical effort and total path effort of the path $"A" \sim "Z"(6pts)$
- c) what are the stage efforts of ND3, NR2 and I for the minimum delay of the path $^{"}A" \sim ^{"}Z"$ (3pts)
- d) determine the widths of ND3, NR2 and I (6pts)
- e) assume that you need to change the above 3-stage logic into one-stage compound logic. Design the compound logic and compare the delay of the compound logic with the above 3-stage logic (14pts)

Use the following parameters for the following questions.

| | | actus tima | clk-to-Q | D-to-Q | contamination | hold | clock skew |
|-----|------|------------|----------|--------|---------------|-------|------------|
| | | setup time | delay | delay | delay | time | Clock skew |
| | FF | 65 ps | 50 ps | n/a | 35 ps | 30 ps | 50 ps |
| lat | ches | 25 ps | 50 ps | 40 ps | 35 ps | 30 ps | 50 ps |

- 2. (15pts) For each of the following sequencing styles, determine the maximum logic propagation delay in each cycle (or half-cycle, for two-phase latches).
 - a) FFs
 - b) two-phase transparent latches with 60ps of nonoverlap between phases
- 3. (17 pts) You need to add testability for a two-bit adder sequencing block using FFs. Draw the RTL level architecture including testability of all the sequential and combinational blocks.
- 4. (5pts) Try to generate a test vector based on the SA1 fault model at ϕ .



5. (28pts) Draw the architecture of a PLL which multiplies frequency by N times at S domain. Also, derive the transfer equations of each sub-block and the corresponding circuit.